

<b>Notice of References Cited</b>	Application/Control No. 10/572,506		Applicant(s)/Patent Under Reexamination JEON ET AL.	
	Examiner Kwang Han		Art Unit 1795	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,746,798	06-2004	Hiratsuka et al.	429/163
*	B	US-5,279,623	01-1994	Watanabe et al.	29/25.03
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	N	WO 99/25036	05-1999	WIPO	Hiratsuka et al.	H01M 2/04
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#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
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